

CERTIFICATE OF ANALYSIS

Product	100 µm chamber depth - 2 analysis chambers	
Slide reference	SC 100-01-02-A-CE	
Batch Machine	432453	L
Production date range (DD-MM-YYYY)	25-10-2024 - 25-10-2024	
Best before (Month-YY)	October-25	

Analysis	Criteria	Result
Dimensions and microscope inspection	20 inspection points	PASSED
Chamber height: <i>Low Coherence Interferometry</i>	Median <5% from indicated mean Variation <2%	PASSED
Average chamber height (µm)		98,18

**WE CERTIFY THAT THE ABOVE MENTIONED PRODUCTS
ARE IN COMPLIANCE WITH OUR SPECIFICATIONS**

Date	October 25, 2024
Name	Anne Linda van Kappel
Qualification	General Manager
Signature	